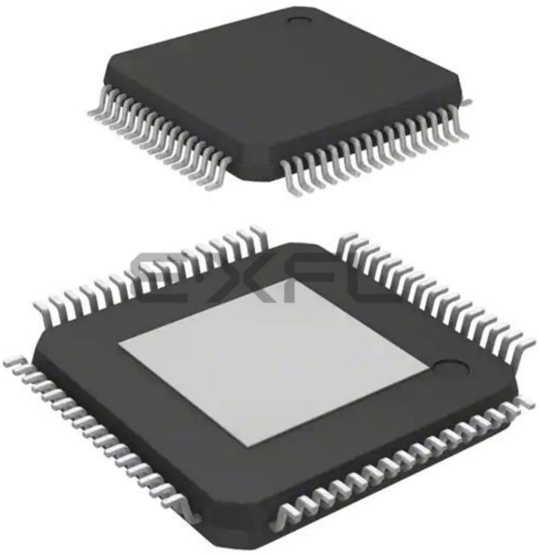

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Details	
Product Status	Not For New Designs
Core Processor	C166SV2
Core Size	16/32-Bit
Speed	80MHz
Connectivity	CANbus, EBI/EMI, I²C, LINbus, SPI, SSC, UART/USART, USI
Peripherals	I²S, POR, PWM, WDT
Number of I/O	38
Program Memory Size	320KB (320K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	34K x 8
Voltage - Supply (Vcc/Vdd)	3V ~ 5.5V
Data Converters	A/D 9x10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 125°C (TA)
Mounting Type	Surface Mount
Package / Case	64-LQFP Exposed Pad
Supplier Device Package	PG-LQFP-64-6
Purchase URL	https://www.e-xfl.com/product-detail/infineon-technologies/xc2734x40f80lrabkxuma1

1.2 Definition of Feature Variants

The XC2734X types are offered with several Flash memory sizes. **Table 2** and **Table 3** describe the location of the available Flash memory.

Table 2 Continuous Flash Memory Ranges

Total Flash Size	1st Range[1)]	2nd Range	3rd Range
320 Kbytes	$C0'0000_H$ … $C0'EFFF_H$	$C1'0000_H$ … $C4'FFFF_H$	n.a.

1) The uppermost 4-Kbyte sector of the first Flash segment is reserved for internal use ($C0'F000_H$ to $C0'FFFF_H$).

Table 3 Flash Memory Module Allocation (in Kbytes)

Total Flash Size	Flash 0[1)]	Flash 1
320	256	64

1) The uppermost 4-Kbyte sector of the first Flash segment is reserved for internal use ($C0'F000_H$ to $C0'FFFF_H$).

The XC2734X types are offered with different interface options. **Table 4** lists the available channels for each option.

Table 4 Interface Channel Association

Total Number	Available Channels / Message Objects
7 ADC0 channels	CH0, CH2, Ch4, CH8, CH10, CH13, CH15
2 ADC1 channels	CH0, CH4
2 CAN nodes	CAN0, CAN1 64 message objects
4 serial channels	U0C0, U0C1, U1C0, U1C1

The XC2734X types are offered with several SRAM memory sizes. **Figure 1** shows the allocation rules for PSRAM and DSRAM. Note that the rules differ:

- PSRAM allocation starts from the **lower** address
- DSRAM allocation starts from the **higher** address

For example 8 Kbytes of PSRAM will be allocated at E0’0000h-E0’1FFFh and 8 Kbytes of DSRAM will be at 00’C000h-00’DFFFh.

Table 5 Pin Definitions and Functions (cont'd)

Pin	Symbol	Ctrl.	Type	Function
47	P10.7	O0 / I	St/B	**Bit 7 of Port 10, General Purpose Input/Output**
	U0C1_DOUT	O1	St/B	**USIC0 Channel 1 Shift Data Output**
	CCU60_COUT63	O2	St/B	**CCU60 Channel 3 Output**
	U0C1_DX0B	I	St/B	**USIC0 Channel 1 Shift Data Input**
	CCU60_CCPOS0A	I	St/B	**CCU60 Position Input 0**
	T4INB	I	St/B	**GPT12E Timer T4 Count/Gate Input**
51	P10.8	O0 / I	St/B	**Bit 8 of Port 10, General Purpose Input/Output**
	U0C0_MCLKOUT	O1	St/B	**USIC0 Channel 0 Master Clock Output**
	U0C1_SELO0	O2	St/B	**USIC0 Channel 1 Select/Control 0 Output**
	CCU60_CCPOS1A	I	St/B	**CCU60 Position Input 1**
	U0C0_DX1C	I	St/B	**USIC0 Channel 0 Shift Clock Input**
	$\overline{\mathrm{BRKIN}}$_B	I	St/B	**OCDS Break Signal Input**
	T3EUDB	I	St/B	**GPT12E Timer T3 External Up/Down Control Input**
52	P10.9	O0 / I	St/B	**Bit 9 of Port 10, General Purpose Input/Output**
	U0C0_SELO4	O1	St/B	**USIC0 Channel 0 Select/Control 4 Output**
	U0C1_MCLKOUT	O2	St/B	**USIC0 Channel 1 Master Clock Output**
	CCU60_CCPOS2A	I	St/B	**CCU60 Position Input 2**
	TCK_B	IH	St/B	**DAP0/JTAG Clock Input** If JTAG pos. B is selected during start-up, an internal pull-up device will hold this pin high when nothing is driving it. If DAP pos. 1 is selected during start-up, an internal pull-down device will hold this pin low when nothing is driving it.
	T3INB	I	St/B	**GPT12E Timer T3 Count/Gate Input**

2.2 Identification Registers

The identification registers describe the current version of the XC2734X and of its modules.

Table 6 XC2734X Identification Registers

Short Name	Value	Address	Notes
SCU_IDMANUF	1820_H	$00'F07E_H$	
SCU_IDCHIP	3001_H	$00'F07C_H$	marking EES-AA or ES-AA
	3002_H	$00'F07C_H$	marking AA, AB
SCU_IDMEM	$304F_H$	$00'F07A_H$	
SCU_IDPROG	1313_H	$00'F078_H$	
JTAG_ID	$0018'B083_H$	---	marking EES-AA or ES-AA
	$1018'B083_H$	---	marking AA, AB

3.1 Memory Subsystem and Organization

The memory space of the XC2734X is configured in the von Neumann architecture. In this architecture all internal and external resources, including code memory, data memory, registers and I/O ports, are organized in the same linear address space.

Table 7 XC2734X Memory Map [1)]

Address Area	Start Loc.	End Loc.	Area Size[2)]	Notes
IMB register space	$FF'FF00_H$	$FF'FFFF_H$	256 Bytes	
Reserved	$F0'0000_H$	$FF'FEFF_H$	< 1 Mbyte	Minus IMB registers
Reserved for EPSRAM	$E8'4000_H$	$EF'FFFF_H$	496 Kbytes	Mirrors EPSRAM
Emulated PSRAM	$E8'0000_H$	$E8'3FFF_H$	up to 16 Kbytes	With Flash timing
Reserved for PSRAM	$E0'4000_H$	$E7'FFFF_H$	496 Kbytes	Mirrors PSRAM
PSRAM	$E0'0000_H$	$E0'3FFF_H$	up to 16 Kbytes	Program SRAM
Reserved for Flash	$C5'0000_H$	$DF'FFFF_H$	1,728 Kbytes	
Flash 1	$C4'0000_H$	$C4'FFFF_H$	64 Kbytes	
Flash 0	$C0'0000_H$	$C3'FFFF_H$	256 Kbytes[3)]	Minus res. seg.
External memory area	$40'0000_H$	$BF'FFFF_H$	8 Mbytes	
External IO area[4)]	$21'0000_H$	$3F'FFFF_H$	1,984 Kbytes	
Reserved	$20'BC00_H$	$20'FFFF_H$	17 Kbytes	
USIC0–2 alternate regs.	$20'B000_H$	$20'BBFF_H$	3 Kbytes	Accessed via EBC
MultiCAN alternate regs.	$20'8000_H$	$20'AFFF_H$	12 Kbytes	Accessed via EBC
Reserved	$20'5800_H$	$20'7FFF_H$	10 Kbytes	
USIC0–2 registers	$20'4000_H$	$20'57FF_H$	6 Kbytes	Accessed via EBC
Reserved	$20'6800_H$	$20'7FFF_H$	6 Kbytes	
MultiCAN registers	$20'0000_H$	$20'3FFF_H$	16 Kbytes	Accessed via EBC
External memory area	$01'0000_H$	$1F'FFFF_H$	1984 Kbytes	
SFR area	$00'FE00_H$	$00'FFFF_H$	0.5 Kbytes	
Dualport RAM (DPRAM)	$00'F600_H$	$00'FDFF_H$	2 Kbytes	
Reserved for DPRAM	$00'F200_H$	$00'F5FF_H$	1 Kbytes	
ESFR area	$00'F000_H$	$00'F1FF_H$	0.5 Kbytes	
XSFR area	$00'E000_H$	$00'EFFF_H$	4 Kbytes	
Data SRAM (DSRAM)	$00'A000_H$	$00'DFFF_H$	16 Kbytes	

Memory Content Protection

The contents of on-chip memories can be protected against soft errors (induced e.g. by radiation) by activating the parity mechanism or the Error Correction Code (ECC).
The parity mechanism can detect a single-bit error and prevent the software from using incorrect data or executing incorrect instructions.
The ECC mechanism can detect and automatically correct single-bit errors. This supports the stable operation of the system.

It is strongly recommended to activate the ECC mechanism wherever possible because this dramatically increases the robustness of an application against such soft errors.

With this hardware most XC2734X instructions are executed in a single machine cycle of 12.5 ns @ 80-MHz CPU clock. For example, shift and rotate instructions are always processed during one machine cycle, no matter how many bits are shifted. Also, multiplication and most MAC instructions execute in one cycle. All multiple-cycle instructions have been optimized so that they can be executed very fast; for example, a 32-/16-bit division is started within 4 cycles while the remaining cycles are executed in the background. Another pipeline optimization, the branch target prediction, eliminates the execution time of branch instructions if the prediction was correct.

The CPU has a register context consisting of up to three register banks with 16 word-wide GPRs each at its disposal. One of these register banks is physically allocated within the on-chip DPRAM area. A Context Pointer (CP) register determines the base address of the active register bank accessed by the CPU at any time. The number of these register bank copies is only restricted by the available internal RAM space. For easy parameter passing, a register bank may overlap others.

A system stack of up to 32 Kwords is provided for storage of temporary data. The system stack can be allocated to any location within the address space (preferably in the on-chip RAM area); it is accessed by the CPU with the stack pointer (SP) register. Two separate SFRs, STKOV and STKUN, are implicitly compared with the stack pointer value during each stack access to detect stack overflow or underflow.

The high performance of the CPU hardware implementation can be best utilized by the programmer with the highly efficient XC2734X instruction set. This includes the following instruction classes:

- Standard Arithmetic Instructions
- DSP-Oriented Arithmetic Instructions
- Logical Instructions
- Boolean Bit Manipulation Instructions
- Compare and Loop Control Instructions
- Shift and Rotate Instructions
- Prioritize Instruction
- Data Movement Instructions
- System Stack Instructions
- Jump and Call Instructions
- Return Instructions
- System Control Instructions
- Miscellaneous Instructions

The basic instruction length is either 2 or 4 bytes. Possible operand types are bits, bytes and words. A variety of direct, indirect or immediate addressing modes are provided to specify the required operands.

Table 8 Compare Modes (cont'd)

Compare Modes	Function
Mode 2	Interrupt-only compare mode; Only one compare interrupt per timer period is generated
Mode 3	Pin set '1' on match; pin reset '0' on compare timer overflow; Only one compare event per timer period is generated
Double Register Mode	Two registers operate on one pin; Pin toggles on each compare match; Several compare events per timer period are possible
Single Event Mode	Generates single edges or pulses; Can be used with any compare mode

When a capture/compare register has been selected for capture mode, the current contents of the allocated timer will be latched ('captured') into the capture/compare register in response to an external event at the port pin associated with this register. In addition, a specific interrupt request for this capture/compare register is generated. Either a positive, a negative, or both a positive and a negative external signal transition at the pin can be selected as the triggering event.

The contents of all registers selected for one of the five compare modes are continuously compared with the contents of the allocated timers.

When a match occurs between the timer value and the value in a capture/compare register, specific actions will be taken based on the compare mode selected.

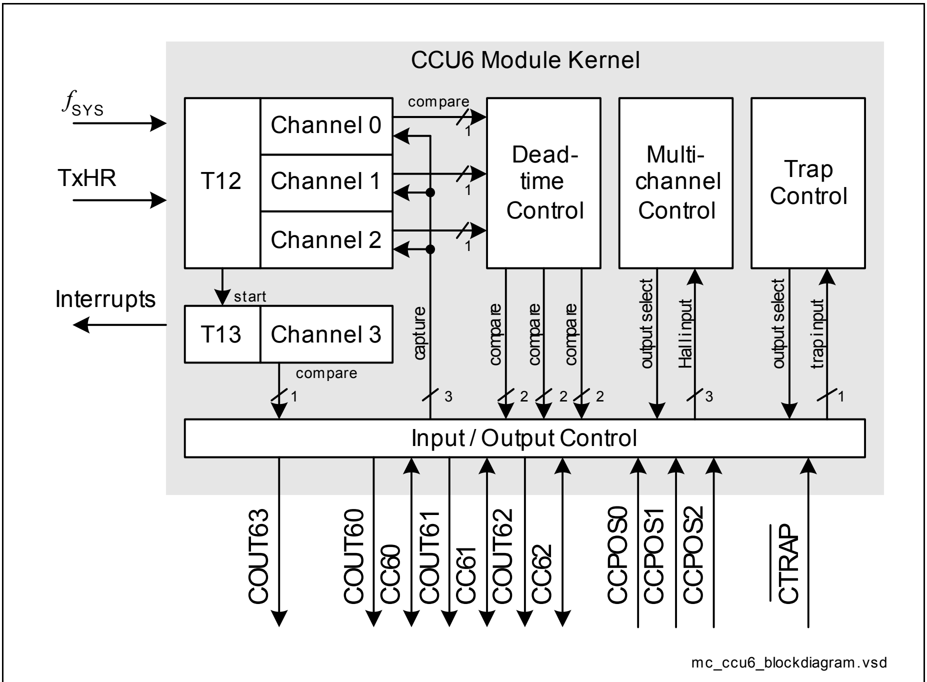

Figure 7 CCU6 Block Diagram

Timer T12 can work in capture and/or compare mode for its three channels. The modes can also be combined. Timer T13 can work in compare mode only. The multi-channel control unit generates output patterns that can be modulated by timer T12 and/or timer T13. The modulation sources can be selected and combined for signal modulation.

With its maximum resolution of 2 system clock cycles, the **GPT2 module** provides precise event control and time measurement. It includes two timers (T5, T6) and a capture/reload register (CAPREL). Both timers can be clocked with an input clock which is derived from the CPU clock via a programmable prescaler or with external signals. The counting direction (up/down) for each timer can be programmed by software or altered dynamically with an external signal on a port pin (TxEUD). Concatenation of the timers is supported with the output toggle latch (T6OTL) of timer T6, which changes its state on each timer overflow/underflow.

The state of this latch may be used to clock timer T5, and/or it may be output on pin T6OUT. The overflows/underflows of timer T6 can also be used to clock the CAPCOM2 timers and to initiate a reload from the CAPREL register.

The CAPREL register can capture the contents of timer T5 based on an external signal transition on the corresponding port pin (CAPIN); timer T5 may optionally be cleared after the capture procedure. This allows the XC2734X to measure absolute time differences or to perform pulse multiplication without software overhead.

The capture trigger (timer T5 to CAPREL) can also be generated upon transitions of GPT1 timer T3 inputs T3IN and/or T3EUD. This is especially advantageous when T3 operates in Incremental Interface Mode.

The RTC module can be used for different purposes:

- System clock to determine the current time and date
- Cyclic time-based interrupt, to provide a system time tick independent of CPU frequency and other resources
- 48-bit timer for long-term measurements
- Alarm interrupt at a defined time

3.11 A/D Converters

For analog signal measurement, up to two 10-bit A/D converters (ADC0, ADC1) with 7 + 2 multiplexed input channels and a sample and hold circuit have been integrated on-chip. 2 inputs can be converted by both A/D converters. Conversions use the successive approximation method. The sample time (to charge the capacitors) and the conversion time are programmable so that they can be adjusted to the external circuit. The A/D converters can also operate in 8-bit conversion mode, further reducing the conversion time.

Several independent conversion result registers, selectable interrupt requests, and highly flexible conversion sequences provide a high degree of programmability to meet the application requirements. Both modules can be synchronized to allow parallel sampling of two input channels.

For applications that require more analog input channels, external analog multiplexers can be controlled automatically. For applications that require fewer analog input channels, the remaining channel inputs can be used as digital input port pins.

The A/D converters of the XC2734X support two types of request sources which can be triggered by several internal and external events.

- Parallel requests are activated at the same time and then executed in a predefined sequence.
- Queued requests are executed in a user-defined sequence.

In addition, the conversion of a specific channel can be inserted into a running sequence without disturbing that sequence. All requests are arbitrated according to the priority level assigned to them.

Data reduction features reduce the number of required CPU access operations allowing the precise evaluation of analog inputs (high conversion rate) even at a low CPU speed. Result data can be reduced by limit checking or accumulation of results.

The Peripheral Event Controller (PEC) can be used to control the A/D converters or to automatically store conversion results to a table in memory for later evaluation, without requiring the overhead of entering and exiting interrupt routines for each data transfer. Each A/D converter contains eight result registers which can be concatenated to build a result FIFO. Wait-for-read mode can be enabled for each result register to prevent the loss of conversion data.

In order to decouple analog inputs from digital noise and to avoid input trigger noise, those pins used for analog input can be disconnected from the digital input stages. This can be selected for each pin separately with the Port x Digital Input Disable registers.

The Auto-Power-Down feature of the A/D converters minimizes the power consumption when no conversion is in progress.

Broken wire detection for each channel and a multiplexer test mode provide information to verify the proper operation of the analog signal sources (e.g. a sensor system).

3.16 Clock Generation

The Clock Generation Unit can generate the system clock signal f_{SYS} for the XC2734X from a number of external or internal clock sources:

- External clock signals with pad voltage or core voltage levels
- External crystal or resonator using the on-chip oscillator
- On-chip clock source for operation without crystal/resonator
- Wake-up clock (ultra-low-power) to further reduce power consumption

The programmable on-chip PLL with multiple prescalers generates a clock signal for maximum system performance from standard crystals, a clock input signal, or from the on-chip clock source. See also **Section 4.7.2**.

The Oscillator Watchdog (OWD) generates an interrupt if the crystal oscillator frequency falls below a certain limit or stops completely. In this case, the system can be supplied with an emergency clock to enable operation even after an external clock failure.

All available clock signals can be output on one of two selectable pins.

4.1.1 Operating Conditions

The following operating conditions must not be exceeded to ensure correct operation of the XC2734X. All parameters specified in the following sections refer to these operating conditions, unless otherwise noticed.

Note: Typical parameter values refer to room temperature and nominal supply voltage, minimum/maximum parameter values also include conditions of minimum/maximum temperature and minimum/maximum supply voltage. Additional details are described where applicable.

Table 12 Operating Conditions

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Voltage Regulator Buffer Capacitance for DMP_M	C_{EVRM} SR	1.0	–	4.7	µF	[1]
Voltage Regulator Buffer Capacitance for DMP_1	C_{EVR1} SR	0.47	–	2.2	µF	[2][1]
External Load Capacitance	C_L SR	–	20[3]	–	pF	pin out driver= default [4]
System frequency	f_{SYS} SR	–	–	80	MHz	[5]
Overload current for analog inputs[6]	I_{OVA} SR	-2	–	5	mA	not subject to production test
Overload current for digital inputs[6]	I_{OVD} SR	-5	–	5	mA	not subject to production test
Overload current coupling factor for analog inputs[7]	K_{OVA} CC	–	2.5 x 10^{-4}	1.5 x 10^{-3}	-	I_{OV}< 0 mA; not subject to production test
		–	1.0 x 10^{-6}	1.0 x 10^{-4}	-	I_{OV}> 0 mA; not subject to production test

4.3.1 DC Parameters for Upper Voltage Area

Keeping signal levels within the limits specified in this table ensures operation without overload conditions. For signal levels outside these specifications, also refer to the specification of the overload current I_{OV}.

Note: Operating Conditions apply.

Table 15 is valid under the following conditions: $V_{DDP} \leq$ 5.5 V; V_{DDP}typ. 5 V; $V_{DDP} \geq$ 4.5 V

Table 15 DC Characteristics for Upper Voltage Range

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Pin capacitance (digital inputs/outputs). To be doubled for double bond pins.[1)]	C_{IO} CC	–	–	10	pF	not subject to production test
Input Hysteresis[2)]	HYS CC	0.11 x V_{DDP}	–	–	V	R_S= 0 Ohm
Absolute input leakage current on pins of analog ports[3)]	$\|I_{OZ1}\|$ CC	–	10	200	nA	$V_{IN}> V_{SS}$; $V_{IN}< V_{DDP}$
Absolute input leakage current for all other pins. To be doubled for double bond pins.[3)1)4)]	$\|I_{OZ2}\|$ CC	–	0.2	5	µA	$T_J \leq$ 110 °C; $V_{IN}> V_{SS}$; $V_{IN}< V_{DDP}$
		–	0.2	15	µA	$T_J \leq$ 150 °C; $V_{IN}> V_{SS}$; $V_{IN}< V_{DDP}$
Pull Level Force Current[5)]	$\|I_{PLF}\|$ SR	250	–	–	µA	$V_{IN} \geq V_{IHmin}$*(pull down_enabled)*; $V_{IN} \leq V_{ILmax}$*(pull up_enabled)*
Pull Level Keep Current[6)]	$\|I_{PLK}\|$ SR	–	–	30	µA	$V_{IN} \geq V_{IHmin}$*(pull up_enabled)*; $V_{IN} \leq V_{ILmax}$*(pull down_enabled)*
Input high voltage (all except XTAL1)	V_{IH} SR	0.7 x V_{DDP}	–	V_{DDP} + 0.3	V	
Input low voltage (all except XTAL1)	V_{IL} SR	-0.3	–	0.3 x V_{DDP}	V	

4.3.2 DC Parameters for Lower Voltage Area

Keeping signal levels within the limits specified in this table ensures operation without overload conditions. For signal levels outside these specifications, also refer to the specification of the overload current I_{OV}.

Note: Operating Conditions apply.

Table 16 is valid under the following conditions: $V_{DDP} \geq 3.0$ V; V_{DDP} typ. 3.3 V; $V_{DDP} \leq 4.5$ V

Table 16 DC Characteristics for Lower Voltage Range

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Pin capacitance (digital inputs/outputs). To be doubled for double bond pins.[1)]	C_{IO} CC	–	–	10	pF	not subject to production test
Input Hysteresis[2)]	HYS CC	0.07 x V_{DDP}	–	–	V	R_S= 0 Ohm
Absolute input leakage current on pins of analog ports[3)]	$\lvert I_{OZ1} \rvert$ CC	–	10	200	nA	$V_{IN} > V_{SS}$; $V_{IN} < V_{DDP}$
Absolute input leakage current for all other pins. To be doubled for double bond pins.[3)1)4)]	$\lvert I_{OZ2} \rvert$ CC	–	0.2	2.5	µA	$T_J \leq 110$ °C; $V_{IN} > V_{SS}$; $V_{IN} < V_{DDP}$
		–	0.2	8	µA	$T_J \leq 150$ °C; $V_{IN} > V_{SS}$; $V_{IN} < V_{DDP}$
Pull Level Force Current[5)]	$\lvert I_{PLF} \rvert$ SR	150	–	–	µA	$V_{IN} \geq V_{IHmin}$ *(pull down)* ; $V_{IN} \leq V_{ILmax}$ *(pull up)*
Pull Level Keep Current[6)]	$\lvert I_{PLK} \rvert$ SR	–	–	10	µA	$V_{IN} \geq V_{IHmin}$ *(pull up)* ; $V_{IN} \leq V_{ILmax}$ *(pull down)*
Input high voltage (all except XTAL1)	V_{IH} SR	0.7 x V_{DDP}	–	V_{DDP} + 0.3	V	
Input low voltage (all except XTAL1)	V_{IL} SR	-0.3	–	0.3 x V_{DDP}	V	

4.3.3 Power Consumption

The power consumed by the XC2734X depends on several factors such as supply voltage, operating frequency, active circuits, and operating temperature. The power consumption specified here consists of two components:

- The switching current I_S depends on the device activity
- The leakage current I_{LK} depends on the device temperature

To determine the actual power consumption, always both components, switching current I_S and leakage current I_{LK} must be added:

$I_{DDP} = I_S + I_{LK}$.

Note: The power consumption values are not subject to production test. They are verified by design/characterization.
To determine the total power consumption for dimensioning the external power supply, also the pad driver currents must be considered.

The given power consumption parameters and their values refer to specific operating conditions:

- **Active mode**:
  Regular operation, i.e. peripherals are active, code execution out of Flash.
- **Stopover mode**:
  Crystal oscillator and PLL stopped, Flash switched off, clock in domain DMP_1 stopped.

Note: The maximum values cover the complete specified operating range of all manufactured devices.
The typical values refer to average devices under typical conditions, such as nominal supply voltage, room temperature, application-oriented activity.
After a power reset, the decoupling capacitors for V_{DDIM} and V_{DDI1} are charged with the maximum possible current.

For additional information, please refer to **Section 5.2**, **Thermal Considerations**.

Note: Operating Conditions apply.

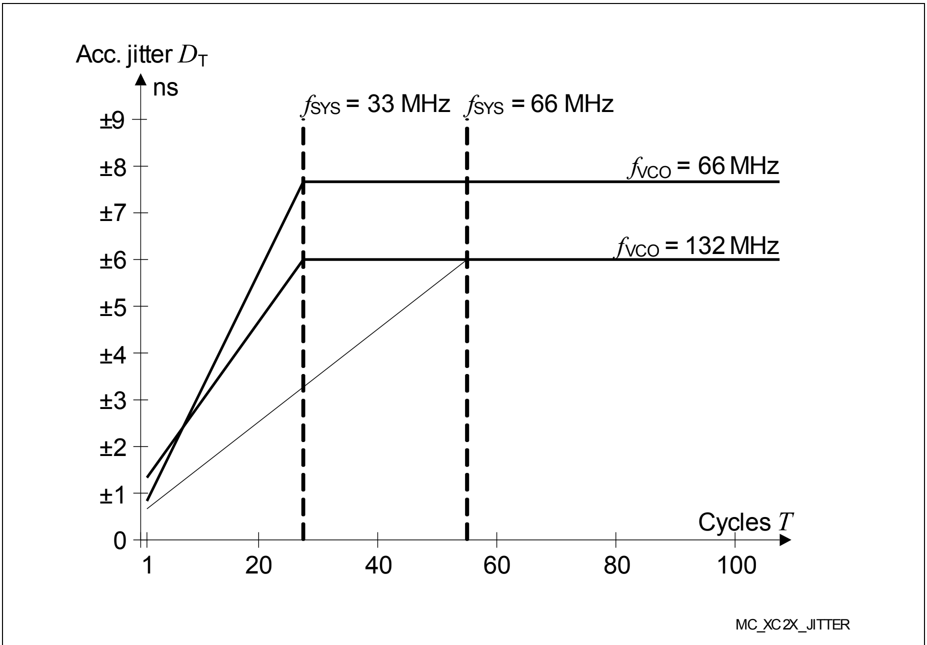

Figure 20 Approximated Accumulated PLL Jitter

Note: The specified PLL jitter values are valid if the capacitive load per pin does not exceed C_L = 20 pF.
The maximum peak-to-peak noise on the pad supply voltage (measured between V_{DDPB} pin 64 and V_{SS} pin 1) is limited to a peak-to-peak voltage of V_{PP} = 50 mV. This can be achieved by appropriate blocking of the supply voltage as close as possible to the supply pins and using PCB supply and ground planes.

PLL frequency band selection

Different frequency bands can be selected for the VCO so that the operation of the PLL can be adjusted to a wide range of input and output frequencies:

Table 28 Standard Pad Parameters for Lower Voltage Range

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Maximum output driver current (absolute value)[1]	I_{Omax} CC	–	–	2.5	mA	Driver_Strength = Medium
		–	–	10	mA	Driver_Strength = Strong
		–	–	0.5	mA	Driver_Strength = Weak
Nominal output driver current (absolute value)	I_{Onom} CC	–	–	1.0	mA	Driver_Strength = Medium
		–	–	2.5	mA	Driver_Strength = Strong
		–	–	0.1	mA	Driver_Strength = Weak

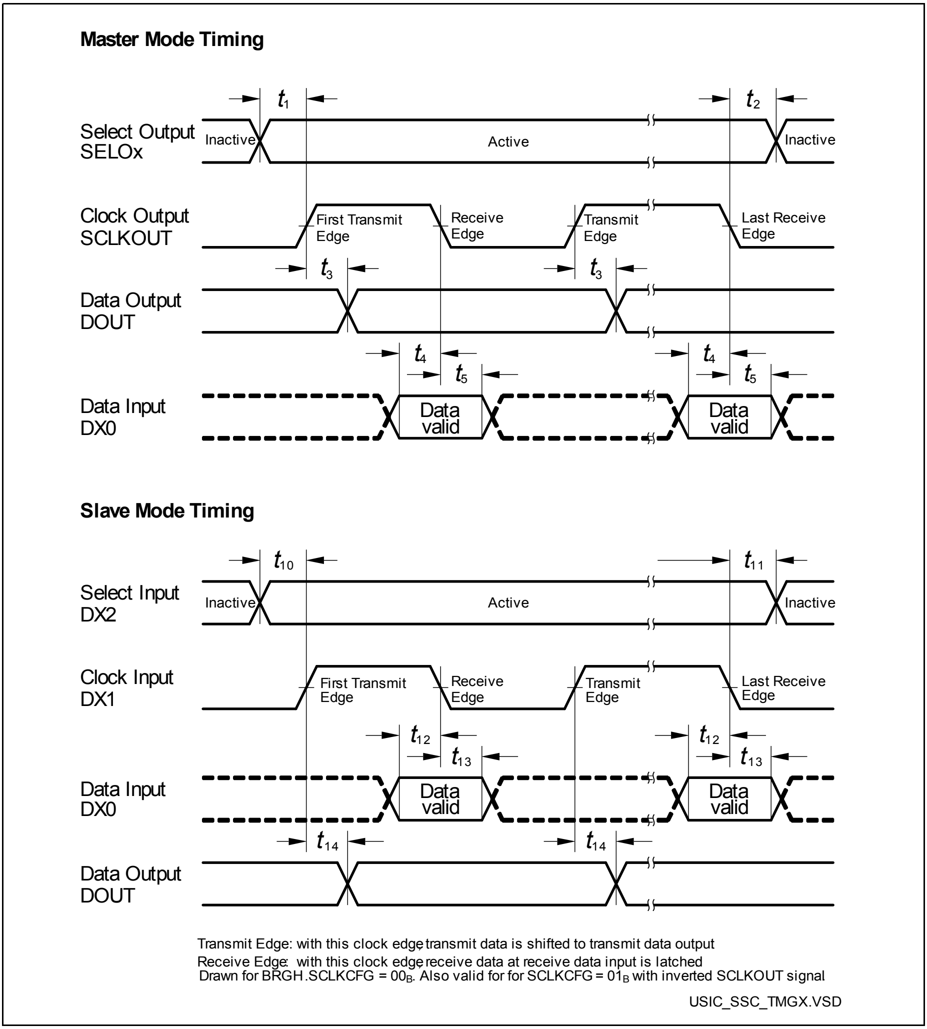

Figure 22 USIC - SSC Master/Slave Mode Timing

Note: This timing diagram shows a standard configuration where the slave select signal is low-active and the serial clock signal is not shifted and not inverted.

Table 35 JTAG Interface Timing for Upper Voltage Range (cont'd)

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
TCK low time	t_3 SR	16	–	–	ns	
TCK clock rise time	t_4 SR	–	–	8	ns	
TCK clock fall time	t_5 SR	–	–	8	ns	
TDI/TMS setup to TCK rising edge	t_6 SR	6	–	–	ns	
TDI/TMS hold after TCK rising edge	t_7 SR	6	–	–	ns	
TDO valid from TCK falling edge (propagation delay)[2)]	t_8 CC	–	25	29	ns	
TDO high impedance to valid output from TCK falling edge[3)2)]	t_9 CC	–	25	29	ns	
TDO valid output to high impedance from TCK falling edge[2)]	t_{10} CC	–	25	29	ns	
TDO hold after TCK falling edge[2)]	t_{18} CC	5	–	–	ns	

1) Under typical conditions, the JTAG interface can operate at transfer rates up to 20 MHz.

2) The falling edge on TCK is used to generate the TDO timing.

3) The setup time for TDO is given implicitly by the TCK cycle time.

Table 36 is valid under the following conditions: C_L= 20 pF; voltage_range= lower

Table 36 JTAG Interface Timing for Lower Voltage Range

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
TCK clock period	t_1 SR	50	–	–	ns	
TCK high time	t_2 SR	16	–	–	ns	
TCK low time	t_3 SR	16	–	–	ns	
TCK clock rise time	t_4 SR	–	–	8	ns	
TCK clock fall time	t_5 SR	–	–	8	ns	
TDI/TMS setup to TCK rising edge	t_6 SR	6	–	–	ns	